	Search Terms
1	CENTER
2	CENTERS
3	CENTRE
4	CENTRES
5	CENTROID
6	CENTROIDS
7	EXTREMA
8	EXTREMAS
9	LASER
10	LASERS
11	MAX
12	MAXES
13	MAXIMA
14	MAXIMUM
15	MAXIMUMS
16	MIN
17	MINIMA
18	MINIMUM
19	MINIMUMS
20	MINS
21	REFLECT
22	REFLECTED
23	REFLECTING
24	REFLECTINGS
25	REFLECTION
26	REFLECTIONS
27	REFLECTS
28	SLOPE
29	SLOPED
30	SLOPES
31	SLOPING
32	TARGET
33	TARGETS
34	SLOPINGS
35	((((SLOPED OR SLOPING OR SLOPE) AND MAXIMA) AND (REFLECT OR REFLECTING OR REFLECTION OR REFLECTED)) AND ((TARGET SAME (CENTROID OR CENTER)) SAME (EXTREMA OR MAXIMA OR MINIMA)) AND LASER)

	Total	USPAT	US-PGPUB	EPO	JPO	Derwent	IBM TDB	USOCR
1	1574456							
2	165363							
3	391993							
4	32910							
5	12840							
6	2917							
7	1915							
8	18							
9	700343							
10	78631							
11	231260							
12	36							
13	23610							
14	1332411							
15	4131							
16	583823							
17	10246							
18	1041024							
19	3303							
20	71952							
21	295469							
22	493363							
23	275671							
24	5							
25	315806							
26	58428							
27	152123							
28	231342							
29	62783							
30	68939							
31	114793							
32	573438							
33	99579							
34	20							
35	106	68	37	0	0	0	1	

	U	1	D cument ID	Issue Date	Pages	Title	Current OR
1	☒	☐	US 20040090553 A1	20040513	317	Monolithic integrated circuit with a printhead interface	348/375
2	☒	☐	US 20040080620 A1	20040429		Integrated circuit for a digital camera system	348/207.2
3	☒	☐	US 20040075821 A1	20040422		Method of capturing and processing sensed images	355/18
4	☒	☐	US 20040075747 A1	20040422		Monolithic integrated circuit having a number of programmable processing elements	348/207.99
5	☒	☐	US 20040065738 A1	20040408		Data distribution mechanism in the form of ink dots on cards	235/454
6	☒	☐	US 20040061734 A1	20040401	310	Printing device for use with a printing cartridge having capacitive sensor identification	347/19
7	☒	☐	US 20040056105 A1	20040325		Data structure encoded on a surface of an object	235/494
8	☒	☐	US 20040051753 A1	20040318		Method of identifying printing cartridge characteristics with capacitive sensors	347/19
9	☒	☐	US 20040041018 A1	20040304		Card having coded data and visible information, for operating a device	235/375
10	☒	☐	US 20040039378 A1	20040226		Selective photocoagulation	606/6
11	☒	☐	US 20040010375 A1	20040115		Methods and apparatus for processing spectral data for use in tissue characterization	702/19
12	☒	☐	US 20040008327 A1	20040115		Image printing apparatus including a microcontroller	355/18
13	☒	☐	US 20040008262 A1	20040115		Utilization of color transformation effects in photographs	348/207.2
14	☒	☐	US 20040008261 A1	20040115		Print roll for use in a camera imaging system	348/207.2
15	☒	☐	US 20040004698 A1	20040108		Programmable camera system with software interpreter	355/18
16	☒	☐	US 20040004651 A1	20040108		Printing cartridge with a data-carrying integrated circuit device	347/86
17	☒	☐	US 20040004129 A1	20040108		Identifying card	235/487
18	☒	☐	US 20030214654 A1	20031120		Spatial averaging technique for ellipsometry and reflectometry	356/369
19	☒	☐	US 20030117496 A1	20030626		Preprinted print rolls for postal use in an image processing device	348/207.2
20	☒	☐	US 20030112419 A1	20030619		Printing cartridge with barcode identification	355/18
21	☒	☐	US 20030103189 A1	20030605		Characterizing aberrations in an imaging lens and applications to visual testing and integrated circuit mask analysis	351/176

	Current XRef	Retrieval Classif	Inventor	S	C	P	2	3	4	5	Image Doc. Displayed	PT
1			Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐	US 20040090553	☐
2			Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
3			Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
4			Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
5			Silverbrook, Kia et al.	☐	☐	☐	☐	☐	☐	☐		☐
6			Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐	US 20040061734	☐
7			Silverbrook, Kia et al.	☐	☐	☐	☐	☐	☐	☐		☐
8			Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
9			Silverbrook, Kia et al.	☐	☐	☐	☐	☐	☐	☐		☐
10			Lin, Charles P.	☐	☐	☐	☐	☐	☐	☐		☐
11			Schomacker, Kevin T. et al.	☐	☐	☐	☐	☐	☐	☐		☐
12			Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
13	348/222.1; 348/231.3; 348/231.7		Silverbrook, Kia et al.	☐	☐	☐	☐	☐	☐	☐		☐
14	348/222.1; 348/239		Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
15			Silverbrook, Kia et al.	☐	☐	☐	☐	☐	☐	☐		☐
16			Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
17			Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
18	257/E21.53		Wei, Lanhua et al.	☐	☐	☐	☐	☐	☐	☐		☐
19			Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
20	355/35; 355/40; 355/41		Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
21	351/177		Neureuther, Andrew R. et al.	☐	☐	☐	☐	☐	☐	☐		☐

	U	1	Document ID	Issue Date	Pages	Title	Current OR
22	☒	☐	US 20030089899 A1	20030515		Nanoscale wires and related devices	257/9
23	☒	☐	US 20030089219 A1	20030515		SYSTEM AND METHOD FOR DISABLING TIME CRITICAL TARGETS	89/1.11
24	☒	☐	US 20030089162 A1	20030515		Dual stage instrument for scanning a specimen	73/105
25	☒	☐	US 20030068185 A1	20030410		Printing cartridge with switch array identification	400/613
26	☒	☐	US 20030047680 A1	20030313		Electroosmotic fluidic device and related methods	250/288
27	☒	☐	US 20030038933 A1	20030227		Calibration apparatus, system and method	356/243.1
28	☒	☐	US 20020130311 A1	20020919		Doped elongated semiconductors, growing such semiconductors, devices including such semiconductors and fabricating such devices	257/1
29	☒	☐	US 20020080335 A1	20020627		Printing cartridge with capacitive sensor identification	355/18
30	☒	☐	US 20020071104 A1	20020613		Image sensing apparatus including a microcontroller	355/18
31	☒	☐	US 20020045284 A1	20020418		Spatial averaging technique for ellipsometry and reflectometry	438/16
32	☒	☐	US 20020033854 A1	20020321		Printing cartridge with pressure sensor array identification	347/17
33	☒	☐	US 20020030713 A1	20020314		Printing cartridge with two dimensional code identification	347/19
34	☒	☐	US 20020030712 A1	20020314		Printing cartridge with an integrated circuit device	347/19
35	☒	☐	US 20020012123 A1	20020131		Spatial averaging technique for ellipsometry and reflectometry	356/369
36	☒	☐	US 20010047682 A1	20011206		Dual stage instrument for scanning a specimen	73/105
37	☒	☐	US 20010022663 A1	20010920		Method for image formation and apparatus for development processing	358/1.9
38	☒	☐	US 6702417 B2	20040309		Printing cartridge with capacitive sensor identification	347/19
39	☒	☐	US 6665454 B1	20031216		Dot adjacency compensation in optical storage systems using ink dots	382/299
40	☒	☐	US 6644771 B1	20031111		Printing cartridge with radio frequency identification	347/19
41	☒	☐	US 6636216 B1	20031021		Digital image warping system	345/427

	Current XRef	Retrieval Classif	Inventor	S	C	P	2	3	4	5	Image Doc. Displayed	PT
22	257/E51.04		Lieber, Charles M. et al.	☐	☐	☐	☐	☐	☐	☐		☐
23			Gorman, Richard	☐	☐	☐	☐	☐	☐	☐		☐
24			Samsavar, Amin et al.	☐	☐	☐	☐	☐	☐	☐		☐
25	355/18		Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
26			Figeys, Daniel et al.	☐	☐	☐	☐	☐	☐	☐		☐
27			Shirley, Lyle G. et al.	☐	☐	☐	☐	☐	☐	☐		☐
28	257/E51.04		Lieber, Charles M. et al.	☐	☐	☐	☐	☐	☐	☐		☐
29	355/38; 355/40; 355/41		Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
30			Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
31	257/E21.53		Wei, Lanhua et al.	☐	☐	☐	☐	☐	☐	☐		☐
32	347/19; 347/5		Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
33	347/5		Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
34	347/86		Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
35	257/E21.53; 438/14		Wei, Lanhua et al.	☐	☐	☐	☐	☐	☐	☐		☐
36			Samsavar, Amin et al.	☐	☐	☐	☐	☐	☐	☐		☐
37	358/518		Ishikawa, Takatoshi et al.	☐	☐	☐	☐	☐	☐	☐		☐
38	347/86; 399/12		Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
39	345/596; 345/698; 358/1.7; 358/1.8; 358/448; 358/453; 382/267; 382/274; 382/282		Silverbrook, Kia et al.	☐	☐	☐	☐	☐	☐	☐		☐
40	347/6		Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
41	345/646		Silverbrook, Kia et al.	☐	☐	☐	☐	☐	☐	☐		☐

	U	1	Document ID	Issue Date	Pages	Title	Current OR
42	☒	☐	US 6618117 B2	20030909		Image sensing apparatus including a microcontroller	355/18
43	☒	☐	US 6594388 B1	20030715		Color image reproduction of scenes with preferential color mapping and scene-dependent tone scaling	382/167
44	☒	☐	US 6584879 B2	20030701		System and method for disabling time critical targets	89/1.11
45	☒	☐	US 6577384 B2	20030610		Spatial averaging technique for ellipsometry and reflectometry	356/73
46	☒	☐	US 6576896 B2	20030610		Electroosmotic fluidic device and related methods	250/288
47	☒	☐	US 6565181 B2	20030520		Printing cartridge with switch array identification	347/19
48	☒	☐	US 6547364 B2	20030415		Printing cartridge with an integrated circuit device	347/19
49	☒	☐	US 6542645 B1	20030401		Adaptive tracking of dots in optical storage system using ink dots	382/254
50	☒	☐	US 6529280 B1	20030304		Three-dimensional measuring device and three-dimensional measuring method	356/602
51	☒	☐	US 6520643 B1	20030218		Image projection system	353/20
52	☒	☐	US 6496280 B2	20021217		Method for image formation and apparatus for development processing	358/1.9
53	☒	☐	US 6476863 B1	20021105		Image transformation means including user interface	348/231.9
54	☒	☐	US 6459495 B1	20021001		Dot center tracking in optical storage systems using ink dots	358/520
55	☒	☐	US 6442525 B1	20020827		System for authenticating physical objects	705/1

	Current XRef	Retrieval Classif	Inventor	S	C	P	2	3	4	5	Image D c. Displayed	PT
42	348/207.99		Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
43	358/520		Gindele, Edward B. et al.	☐	☐	☐	☐	☐	☐	☐		☐
44			Gorman, Richard	☐	☐	☐	☐	☐	☐	☐		☐
45	257/E21.53; 356/369; 356/445		Wei, Lanhua et al.	☐	☐	☐	☐	☐	☐	☐		☐
46			Figeys, Daniel et al.	☐	☐	☐	☐	☐	☐	☐		☐
47	347/214; 347/86; 399/12		Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
48	347/86		Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
49	235/437; 382/309		Silverbrook, Kia et al.	☐	☐	☐	☐	☐	☐	☐		☐
50	356/606		Yahashi, Akira et al.	☐	☐	☐	☐	☐	☐	☐		☐
51	349/9		Holman, Robert L. et al.	☐	☐	☐	☐	☐	☐	☐		☐
52	358/3.27; 358/518; 358/527; 358/532		Ishikawa, Takatoshi et al.	☐	☐	☐	☐	☐	☐	☐		☐
53			Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
54			Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
55	235/379; 235/380; 235/382; 348/441; 348/460; 348/552; 380/30; 705/51; 705/52; 705/64; 705/67; 705/71; 713/169; 713/180		Silverbrook, Kia et al.	☐	☐	☐	☐	☐	☐	☐		☐

	U	1	Document ID	Issue Date	Pages	Title	Current OR
56	☒	☐	US 6431669 B1	20020813		Method and apparatus for information storage in a portable print roll	347/2
57	☒	☐	US 6416154 B1	20020709		Printing cartridge with two dimensional code identification	347/19
58	☒	☐	US 6415054 B1	20020702		Target detection for dot region alignment in optical storage systems using ink dots	382/233
59	☒	☐	US 6396069 B1	20020528		Topographer for real time ablation feedback having synthetic wavelength generators	250/559.22
60	☒	☐	US 6375327 B2	20020423		Image projection system	353/20
61	☒	☐	US 6362869 B1	20020326		Authentication system for camera print rolls	355/18
62	☒	☐	US 6362868 B1	20020326		Print media roll and ink replaceable cartridge	355/18
63	☒	☐	US 6356715 B1	20020312		Prints remaining indicating for camera with variable length print capability	396/284
64	☒	☐	US 6317192 B1	20011113		Utilization of image tiling effects in photographs	355/18
65	☒	☐	US 6315412 B1	20011113		Method and apparatus for measuring visual sensitivity and optical properties of components of the eye	351/200
66	☒	☐	US 6315200 B1	20011113		Encoded data card reading system	235/454
67	☒	☐	US 6306036 B1	20011023		Computer game with replaceable character heads	463/31
68	☒	☐	US 6281027 B1	20010828		Spatial averaging technique for ellipsometry and reflectometry	438/14
69	☒	☐	US 6267005 B1	20010731		Dual stage instrument for scanning a specimen	73/105
70	☒	☐	US 6217165 B1	20010417		Ink and media cartridge with axial ink chambers	347/86
71	☒	☐	US 6213606 B1	20010410		Image projection system	353/20
72	☒	☐	US 6207360 B1	20010327		Method for image formation and apparatus for development processing	430/434
73	☒	☐	US 6141105 A	20001031		Three-dimensional measuring device and three-dimensional measuring method	356/623

	Current XRef	Retrieval Classif	Inventor	S	C	P	2	3	4	5	Image Doc. Displayed	PT
56	358/296		Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
57	347/14		Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
58			Silverbrook, Kia et al.	☐	☐	☐	☐	☐	☐	☐		☐
59			MacPherson, David C. et al.	☐	☐	☐	☐	☐	☐	☐		☐
60	349/9; 359/501		Holman, Robert L. et al.	☐	☐	☐	☐	☐	☐	☐		☐
61	347/101; 347/19		Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
62	347/86; 355/72; 399/12		Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
63	347/101; 396/429; 396/515		Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
64	347/2; 348/222.1; 396/429		Silverbrook, Kia et al.	☐	☐	☐	☐	☐	☐	☐		☐
65	351/208		Snodderly, D. Max et al.	☐	☐	☐	☐	☐	☐	☐		☐
66	235/462.01; 235/462.1; 235/462.24; 235/470		Silverbrook, Kia et al.	☐	☐	☐	☐	☐	☐	☐		☐
67	463/32		Burns, Patrick et al.	☐	☐	☐	☐	☐	☐	☐		☐
68	257/E21.53; 438/15; 438/16		Wei, Lanhua et al.	☐	☐	☐	☐	☐	☐	☐		☐
69	250/306		Samsavar, Amin et al.	☐	☐	☐	☐	☐	☐	☐		☐
70			Silverbrook, Kia	☐	☐	☐	☐	☐	☐	☐		☐
71	349/9; 359/501		Holman, Robert L. et al.	☐	☐	☐	☐	☐	☐	☐		☐
72	430/419; 430/428; 430/963		Ishikawa, Takatoshi et al.	☐	☐	☐	☐	☐	☐	☐		☐
73			Yahashi, Akira et al.	☐	☐	☐	☐	☐	☐	☐		☐

	U	1	Document ID	Issue Date	Pages	Title	Current OR
74	☒	☐	US 6067391 A	20000523		Multiply periodic refractive index modulated optical filters	385/27
75	☒	☐	US 6000612 A	19991214		Portable data collection device having optical character recognition	235/454
76	☒	☐	US 5986761 A	19991116		Laser-based inspection tool for disk defects and curvature	356/600
77	☒	☐	US 5975703 A	19991102		Image projection system	353/20
78	☒	☐	US 5948972 A	19990907		Dual stage instrument for scanning a specimen	73/105
79	☒	☐	US 5905567 A	19990518		Method and apparatus for optimizing sub-pixel resolution in a triangulation based distance measuring device	356/3.06
80	☒	☐	US 5844140 A	19981201		Ultrasound beam alignment servo	73/633
81	☒	☐	US 5818383 A	19981006		Interferometric moving vehicle imaging apparatus and method	342/109
82	☒	☐	US 5731994 A	19980324		Method of packing particles into vessels and apparatus therefor	702/128
83	☒	☐	US 5671200 A	19970923		Method for detecting the movement of a light beam and optical information reproduction apparatus using the same	369/44.28
84	☒	☐	US 5627635 A	19970506		Method and apparatus for optimizing sub-pixel resolution in a triangulation based distance measuring device	356/3.06
85	☒	☐	US 5587463 A	19961224		Texaphyrin macrocycles and metal complexes thereof	534/15

	Current XRef	Retrieval Classif	Inventor	S	C	P	2	3	4	5	Image Doc. Displayed	PT
74	385/37		Land, Peter L.	☐	☐	☐	☐	☐	☐	☐		☐
75	235/462.11; 235/462.45; 382/176		Xu, Jianhua	☐	☐	☐	☐	☐	☐	☐		☐
76			Crawforth, Linden et al.	☐	☐	☐	☐	☐	☐	☐		☐
77	349/9; 359/501		Holman, Robert L. et al.	☐	☐	☐	☐	☐	☐	☐		☐
78			Samsavar, Amin et al.	☐	☐	☐	☐	☐	☐	☐		☐
79	250/201.6; 250/559.25; 356/613; 356/628		Dewan, Brian	☐	☐	☐	☐	☐	☐	☐		☐
80	310/90.5; 600/437; 600/443; 600/453; 73/620; 73/621		Seale, Joseph B.	☐	☐	☐	☐	☐	☐	☐		☐
81	342/161		Stockburger, Edward F. et al.	☐	☐	☐	☐	☐	☐	☐		☐
82	141/1; 141/286; 422/219; 422/232; 422/301; 73/865.5		Okubo, Shuichi et al.	☐	☐	☐	☐	☐	☐	☐		☐
83	369/44.29; 369/44.35		Yamaguchi, Osamu et al.	☐	☐	☐	☐	☐	☐	☐		☐
84	250/201.6; 250/559.25; 356/627		Dewan, Brian	☐	☐	☐	☐	☐	☐	☐		☐
85	534/11; 540/145; 540/465; 540/472; 540/474		Sessler, Jonathan L. et al.	☐	☐	☐	☐	☐	☐	☐		☐

	U	1	Document ID	Issue Date	Pages	Title	Current OR
86	☒	☐	US 5525325 A	19960611		Expanded porphyrins: large porphyrin-like tripyrroledimethine-derived macrocycles	424/9.6
87	☒	☐	US 5520356 A	19960528		System for propelling and guiding a solid object with a beam of electromagnetic radiation	244/62
88	☒	☐	US 5369101 A	19941129		Expanded porphyrins: large porphyrin-like tripyrroledimethine-derived macrocycles	534/13
89	☒	☐	US 5293312 A	19940308		Method and apparatus for computing tomographic scans	378/14
90	☒	☐	US 5292414 A	19940308		Expanded porphyrins: large porphyrin-like tripyrroledimethine-derived macrocycles for singlet oxygen production	204/157.5
91	☒	☐	US 5272142 A	19931221		Expanded porphyrins: large porphyrin-like tripyrroledimethine-derived macrocycles and methods for treating tumors	514/185
92	☒	☐	US 5256399 A	19931026		Aromatic pentadentate expanded porphyrins in magnetic resonance imaging	424/9.362
93	☒	☐	US 5179383 A	19930112		Synthetic aperture radar processor to handle large squint with high phase and geometric accuracy	342/25
94	☒	☐	US 5162509 A	19921110		Process for preparing expanded porphyrins: large porphyrin-like tripyrroledimethine-derived macrocycles	534/15
95	☒	☐	US 5112126 A	19920512		Apparatuses and methods for making geophysical measurements useful in determining the deflection of the vertical	356/141.5

	Current XRef	Retrieval Classif	Inventor	S	C	P	2	3	4	5	Image Doc. Displayed	PT
86	424/9.61; 435/2; 436/2; 514/185; 514/410; 514/836; 540/145; 540/472		Sessler, Jonathan L. et al.	☐	☐	☐	☐	☐	☐	☐		☐
87	244/172; 60/203.1		Ensley, Donald L.	☐	☐	☐	☐	☐	☐	☐		☐
88	534/16; 540/145; 540/465; 540/472		Sessler, Jonathan L. et al.	☐	☐	☐	☐	☐	☐	☐		☐
89			Waggener, Robert G.	☐	☐	☐	☐	☐	☐	☐		☐
90			Sessler, Jonathan L. et al.	☐	☐	☐	☐	☐	☐	☐		☐
91	435/2; 514/836; 514/908; 534/15; 540/145		Sessler, Jonathan L. et al.	☐	☐	☐	☐	☐	☐	☐		☐
92	436/173; 436/806; 514/185; 514/836; 534/15; 540/145		Sessler, Jonathan L. et al.	☐	☐	☐	☐	☐	☐	☐		☐
93	342/25D		Raney, R. K. et al.	☐	☐	☐	☐	☐	☐	☐		☐
94	534/16; 540/465; 540/472		Sessler, Jonathan L. et al.	☐	☐	☐	☐	☐	☐	☐		☐
95	33/283; 33/304; 33/306; 33/309; 356/148; 356/149; 356/250		Graebner, Peter	☐	☐	☐	☐	☐	☐	☐		☐

	U	1	Document ID	Issue Date	Pages	Title	Current OR
96	☒	☐	US 5020411 A	19910604		Mobile assault logistic kinetmatic engagement device	89/1.11
97	☒	☐	US 4935498 A	19900619		Expanded porphyrins: large porphyrin-like tripyrroledimethine-derived macrocycles	534/15
98	☒	☐	US 4914725 A	19900403		Transducer positioning servo mechanisms employing digital and analog circuits	318/560
99	☒	☐	US 4825394 A	19890425		Vision metrology system	356/147
100	☒	☐	US 4807131 A	19890221		Grading system	701/50
101	☒	☐	US 4735762 A	19880405		Laser or charged-particle-beam fusion reactor with direct electric generation by magnetic flux compression	376/102
102	☒	☐	US 4666295 A	19870519		Linear FM chirp laser	356/5.09
103	☒	☐	US 3847080 A	19741112		REMOTE ROCK BREAKING METHOD APPARATUS THEREFOR	102/311
104	☒	☐	US 3741119 A	19730626		REMOTE ROCK BREAKING METHOD APPARATUS THEREFOR	102/310
105	☒	☐	US 3644043 A	19720222		INTEGRATED INFRARED-TRACKER-RECEIVER LASER-RANGEFINDER TARGET SEARCH AND TRACK SYSTEM	356/5.08
106	☒	☐	NN9202136	19920201		Scan Angle Multiplying and Twisted Mirrors for Bar Code Scanner or Laser Printer.	

	Current XRef	Retrieval Classif	Inventor	S	C	P	2	3	4	5	Image D c. Displayed	PT
96	376/319; 60/203.1; 89/8		Rowan, Larry	☐	☐	☐	☐	☐	☐	☐		☐
97	534/11; 540/145; 540/465; 540/477		Sessler, Jonathan L. et al.	☐	☐	☐	☐	☐	☐	☐		☐
98	318/561; 318/563; 360/77.06; 360/77.08; 360/78.05		Belser, Karl A. et al.	☐	☐	☐	☐	☐	☐	☐		☐
99			Beamish, Jerald K. et al.	☐	☐	☐	☐	☐	☐	☐		☐
100	172/4.5; 37/382; 37/907		Clegg, Philip M.	☐	☐	☐	☐	☐	☐	☐		☐
101	376/101; 376/146; 376/147; 376/152; 976/DIG.3		Lasche, George P.	☐	☐	☐	☐	☐	☐	☐		☐
102	342/201; 356/28.5; 359/321; 372/12; 372/28; 372/32		Duvall, III, Robert L. et al.	☐	☐	☐	☐	☐	☐	☐		☐
103			Eckels, Robert E.	☐	☐	☐	☐	☐	☐	☐		☐
104	102/311		Eckels, Robert E.	☐	☐	☐	☐	☐	☐	☐		☐
105	250/203.1; 250/203.3; 356/141.1; 356/141.5; 89/41.06		Jones, Sheldon et al.	☐	☐	☐	☐	☐	☐	☐		☐
106				☐	☐	☐	☐	☐	☐	☐		☐

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2	25	20	4	1	0	0	0	

	U	1	Document ID	Issue Date	Pages	Title	Current OR
1	☐	☐	US 20030232253 A1	20031218	10	Techniques to characterize iso-dense effects for microdevice manufacture	430/5
2	☒	☐	US 20030152848 A1	20030814	12	Calibration wafer for a stepper	430/22
3	☒	☐	US 20020048922 A1	20020425	21	Semiconductor processing methods and structures for determining alignment during semiconductor wafer processing	438/597
4	☒	☐	US 20010051441 A1	20011213	21	SEMICONDUCTOR PROCESSING METHODS AND STRUCTURES FOR DETERMINING ALIGNMENT DURING SEMICONDUCTOR WAFER PROCESSING	438/758
5	☒	☐	US 6671048 B1	20031230	18	Method for determining wafer misalignment using a pattern on a fine alignment target	356/401
6	☒	☐	US 6639676 B1	20031028	29	Method for determining rotational error portion of total misalignment error in a stepper	356/401
7	☒	☐	US 6544859 B2	20030408	20	Semiconductor processing methods and structures for determining alignment during semiconductor wafer processing	438/401
8	☒	☐	US 6541283 B1	20030401	30	Method for determining magnification error portion of total misalignment error in a stepper	438/7
9	☒	☐	US 6465322 B2	20021015	22	Semiconductor processing methods and structures for determining alignment during semiconductor wafer processing	438/401
10	☒	☐	US 6301008 B1	20011009	15	Arrangement and method for calibrating optical line shortening measurements	356/401
11	☒	☐	US 6258611 B1	20010710	19	Method for determining translation portion of misalignment error in a stepper	438/14
12	☒	☐	US 5976741 A	19991102	14	Methods for determining illumination exposure dosage	430/30
13	☒	☐	US 5972051 A	19991026	9	Method and apparatus for removing particles from semiconductor wafer edges using a particle withdrawing means	29/25.01
14	☒	☐	US 5962173 A	19991005	9	Method for measuring the effectiveness of optical proximity corrections	430/5
15	☒	☐	US 5960107 A	19990928	17	Method for verifying an average topography height function of a photostepper	382/145

	Current XRef	Retrieval Classif	Inventor	S	C	P	2	3	4	5	Image D c. Displayed	PT
1	250/311; 430/30; 430/311		Leroux, Pierre et al.	☒	☐	☐	☐	☐	☐	☐	US 20030232253	☐
2			Leroux, Pierre et al.	☐	☐	☐	☐	☐	☐	☐	US 20030152848	☐
3			Ziger, David et al.	☐	☐	☐	☐	☐	☐	☐	US 20020048922	☐
4			ZIGER, DAVID et al.	☐	☐	☐	☐	☐	☐	☐	US 20010051441	☐
5			Leroux, Pierre	☐	☐	☐	☐	☐	☐	☐	US 6671048	☐
6			Leroux, Pierre	☐	☐	☐	☐	☐	☐	☐	US 6639676	☐
7	438/14; 438/975		Ziger, David et al.	☐	☐	☐	☐	☐	☐	☐	US 6544859	☐
8	430/311		Leroux, Pierre	☐	☐	☐	☐	☐	☐	☐	US 6541283	☐
9	148/DIG.102; 438/14; 438/975		Ziger, David et al.	☐	☐	☐	☐	☐	☐	☐	US 6465322	☐
10	250/559.3; 356/400		Ziger, David et al.	☐	☐	☐	☐	☐	☐	☐	US 6301008	☐
11	430/312; 430/394; 430/396; 438/16; 438/401		Leroux, Pierre	☐	☐	☐	☐	☐	☐	☐	US 6258611	☐
12	382/145		Ziger, David et al.	☐	☐	☐	☐	☐	☐	☐	US 5976741	☐
13	134/1.3; 15/1.51; 257/E21.214; 438/906		Leroux, Pierre et al.	☐	☐	☐	☐	☐	☐	☐	US 5972051	☐
14	356/620; 430/22; 430/394		Leroux, Pierre et al.	☐	☐	☐	☐	☐	☐	☐	US 5962173	☐
15	356/618		Leroux, Pierre	☐	☐	☐	☐	☐	☐	☐	US 5960107	☐

	U	1	Document ID	Issue Date	Pages	Title	Current OR
16	☒	☐	US 5902703 A	19990511	8	Method for measuring dimensional anomalies in photolithographed integrated circuits using overlay metrology, and masks therefor	430/5
17	☒	☐	US 5876883 A	19990302	13	Method forming focus/exposure matrix on a wafer using overlapped exposures	430/22
18	☒	☐	US 5856052 A	19990105	13	Wafer with a focus/exposure matrix	430/18
19	☒	☐	US 5830610 A	19981103	14	Method for measuring alignment accuracy in a step and repeat system utilizing different intervals	430/22
20	☒	☐	US 5780208 A	19980714	8	Method and mask design to minimize reflective notching effects	430/394
21	☒	☐	US 5762688 A	19980609	7	Particle removal wafer	95/212
22	☒	☐	US 5407785 A	19950418	5	Method for generating dense lines on a semiconductor wafer using phase-shifting and multiple exposures	430/312
23	☒	☐	US 5392113 A	19950221	6	Semiconductor wafer defect monitoring	356/237.5
24	☒	☐	US 5350428 A	19940927	11	Electrostatic apparatus and method for removing particles from semiconductor wafers	29/25.01
25	☒	☐	FR 2727663 A1	19960607		TITLE DATA NOT AVAILABLE	

	Current XRef	Retrieval Classif	Inventor	S	C	P	2	3	4	5	Image Doc. Displayed	PT
16	356/614; 430/22; 430/394		Leroux, Pierre et al.	☐	☐	☐	☐	☐	☐	☐	US 5902703	☐
17	430/312; 430/394		Leroux, Pierre	☐	☐	☐	☐	☐	☐	☐	US 5876883	☐
18	430/9		Leroux, Pierre	☐	☐	☐	☐	☐	☐	☐	US 5856052	☐
19	356/399; 356/401; 382/145; 382/151		Leroux, Pierre et al.	☐	☐	☐	☐	☐	☐	☐	US 5830610	☐
20	250/492.22; 430/322; 430/396; 430/494		Ziger, David et al.	☐	☐	☐	☐	☐	☐	☐	US 5780208	☐
21	55/282; 95/237		Ziger, David H. et al.	☐	☐	☐	☐	☐	☐	☐	US 5762688	☐
22	430/328; 430/394; 430/396; 430/397		Leroux, Pierre	☐	☐	☐	☐	☐	☐	☐	US 5407785	☐
23	250/559.45		Sayka, Anthony et al.	☐	☐	☐	☐	☐	☐	☐	US 5392113	☐
24	134/1.3; 15/1.51; 438/906		Leroux, Pierre et al.	☐	☐	☐	☐	☐	☐	☐	US 5350428	☐
25			LEROUX, PIERRE et al.	☐	☐	☐	☐	☐	☐	☐		☐

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